TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

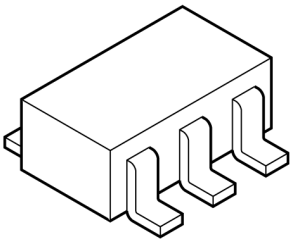
TC7SZ125F,TC7SZ125FU

Bus Buffer 3-State Output

Features

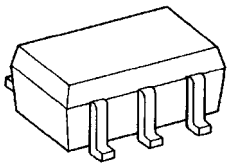
- High output drive: ±24 mA (min) @V_{CC} = 3 V
- Super high speed operation:
  t_{pd} 2.6 ns (typ.) @V_{CC} = 5 V, 50 pF
- Operation voltage range: $V_{CC\ (opr)}$ = 1.8~5.5 V
- Power down protection is provided on all inputs and outputs.
- Matches the performance of TC74LCX series when operated at 3.3 V V_{CC}.

TC7SZ125F



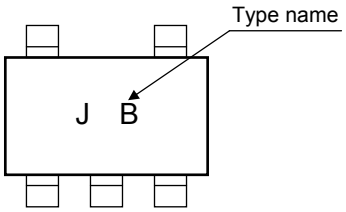
SSOP5-P-0.95

TC7SZ125FU



SSOP5-P-0.65A

Marking

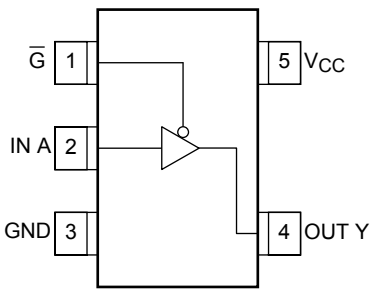


Weight
SSOP5-P-0.95 : 0.016 g (typ.)
SSOP5-P-0.65A : 0.006 g (typ.)

Absolute Maximum Ratings (Ta = 25°C)

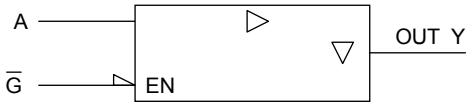
Characteristics	Symbol	Rating	Unit
Power supply voltage	V_{CC}	−0.5~6	V
DC input voltage	V_{IN}	−0.5~6	V
DC output voltage	V_{OUT}	−0.5~6	V
Input diode current	I_{IK}	±20	mA
Output diode current	I_{OK}	±20	mA
DC output current	I_{OUT}	±50	mA
DC V_{CC}/ground current	I_{CC}	±50	mA
Power dissipation	P_D	200	mW
Storage temperature	T_{stg}	−65~150	°C
Lead temperature (10s)	T_L	260	°C

Pin Assignment (top view)



Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook (“Handling Precautions”/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Logic Diagram



Truth Table

Input		Output
A	$\overline{G}$	Y
X	H	Z
L	L	L
H	L	H

X: Don't Care
Z: High Impedance

Operating Ranges

Characteristics	Symbol	Rating	Unit
Supply voltage	V_{CC}	1.8~5.5	V
		1.5~5.5 (Note 1)	
Input voltage	V_{IN}	0~5.5	V
Output voltage	V_{OUT}	0~5.5 (Note 2)	V
		0~V_{CC} (Note 3)	
Operating temperature	T_{opr}	−40~85	°C
Input rise and fall time	dt/dv	0~20 (V_{CC} = 1.8 V, 2.5 V ± 0.2 V)	ns/V
		0~10 (V_{CC} = 3.3 V ± 0.3 V)	
		0~5 (V_{CC} = 5.5 V ± 0.5 V)	

Note 1: Data retention only

Note 2: V_{CC} = 0 V

Note 3: H and Low state

Electrical Characteristics

DC Characteristics

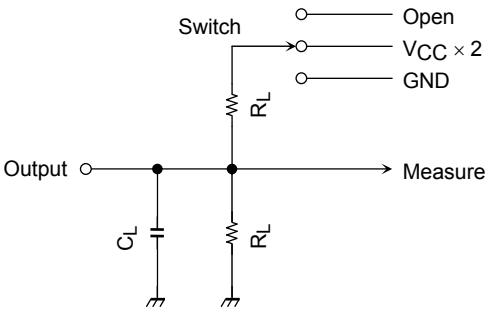
Characteristics		Symbol	Test Condition		V_{CC} (V)	Ta = 25°C			Ta = −40~85°C		Unit
						Min	Typ.	Max	Min	Max	
Input voltage	High level	V_{IH}	—		1.8	0.88 × V_{CC}	—	—	0.88 × V_{CC}	—	V
					2.3~5.5	0.75 × V_{CC}	—	—	0.75 × V_{CC}	—	
	Low level	V_{IL}	—		1.8	—	—	0.12 × V_{CC}	—	0.12 × V_{CC}	
					2.3~5.5	—	—	0.25 × V_{CC}	—	0.25 × V_{CC}	
Output voltage	High level	V_{OH}	V_{IN} = V_{IH}	I_{OH} = −100 μA	1.8	1.7	1.8	—	1.7	—	V
					2.3	2.2	2.3	—	2.2	—	
					3.0	2.9	3.0	—	2.9	—	
					4.5	4.4	4.5	—	4.4	—	
				I_{OH} = −8 mA	2.3	1.9	2.15	—	1.9	—	
				I_{OH} = −16 mA	3.0	2.4	2.8	—	2.4	—	
				I_{OH} = −24 mA	3.0	2.3	2.68	—	2.3	—	
				I_{OH} = −32 mA	4.5	3.8	4.2	—	3.8	—	
	Low level	V_{OL}	V_{IN} = V_{IL}	I_{OL} = 100 μA	1.8	—	0	0.1	—	0.1	
					2.3	—	0	0.1	—	0.1	
					3.0	—	0	0.1	—	0.1	
					4.5	—	0	0.1	—	0.1	
				I_{OL} = 8 mA	2.3	—	0.1	0.3	—	0.3	
				I_{OL} = 16 mA	3.0	—	0.15	0.4	—	0.4	
				I_{OL} = 24 mA	3.0	—	0.22	0.55	—	0.55	
				I_{OL} = 32 mA	4.5	—	0.22	0.55	—	0.55	
Input leakage current		I_{IN}	V_{IN} = 5.5 V or GND		0~5.5	—	—	±1	—	±10	μA
3-state output off-state current		I_{OZ}	V_{IN} = V_{IH} or V_{IL} V_{OUT} = 0~5.5 V		1.8~5.5	—	—	±1	—	±10	μA
Power off leakage current		I_{OFF}	V_{IN} or V_{OUT} = 5.5 V		0.0	—	—	1	—	10	μA
Quiescent supply current		I_{CC}	V_{IN} = V_{CC} or GND		5.5	—	—	2	—	20	μA

AC Characteristics (unless otherwise specified, Input: $t_r = t_f = 3$ ns)

Characteristics	Symbol	Test Condition		Ta = 25°C			Ta = −40~85°C		Unit
			V_{CC} (V)	Min	Typ.	Max	Min	Max	
Propagation delay time	t_{pLH} t_{pHL}	C_L = 15 pF, R_L = 1 MΩ	1.8	2.0	5.3	11.0	2.0	11.5	ns
			2.5 ± 0.2	0.8	3.4	7.5	0.8	8.0	
			3.3 ± 0.3	0.5	2.5	5.2	0.5	5.5	
			5.0 ± 0.5	0.5	2.1	4.5	0.5	4.8	
		C_L = 50 pF, R_L = 500 Ω	3.3 ± 0.3	1.5	3.2	5.7	1.5	6.0	
			5.0 ± 0.5	0.8	2.6	5.0	0.8	5.3	
Output enable time	t_{pZL} t_{pZH}	C_L = 50 pF, R_L = 500 Ω	1.8	2.0	7.0	12.5	2.0	13.0	ns
			2.5 ± 0.2	1.5	4.6	8.5	1.5	9.0	
			3.3 ± 0.3	1.5	3.5	6.2	1.5	6.5	
			5.0 ± 0.5	0.8	2.8	5.5	0.8	5.8	
Output disable time	t_{pLZ} t_{pHZ}	C_L = 50 pF, R_L = 500 Ω	1.8	2.0	5.4	11.0	2.0	12.0	ns
			2.5 ± 0.2	1.5	3.5	8.0	1.5	8.5	
			3.3 ± 0.3	1.0	2.8	5.7	1.0	6.0	
			5.0 ± 0.5	0.5	2.1	4.7	0.5	5.0	
Input capacitance	C_{IN}	—	0~5.5	—	4	—	—	—	pF
Power dissipation capacitance	C_{PD}	(Note 4)	3.3	—	17	—	—	—	pF
			5.5	—	24	—	—	—	

Note 4: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.
Average operating current can be obtained by the equation:
$I_{CC\ (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$

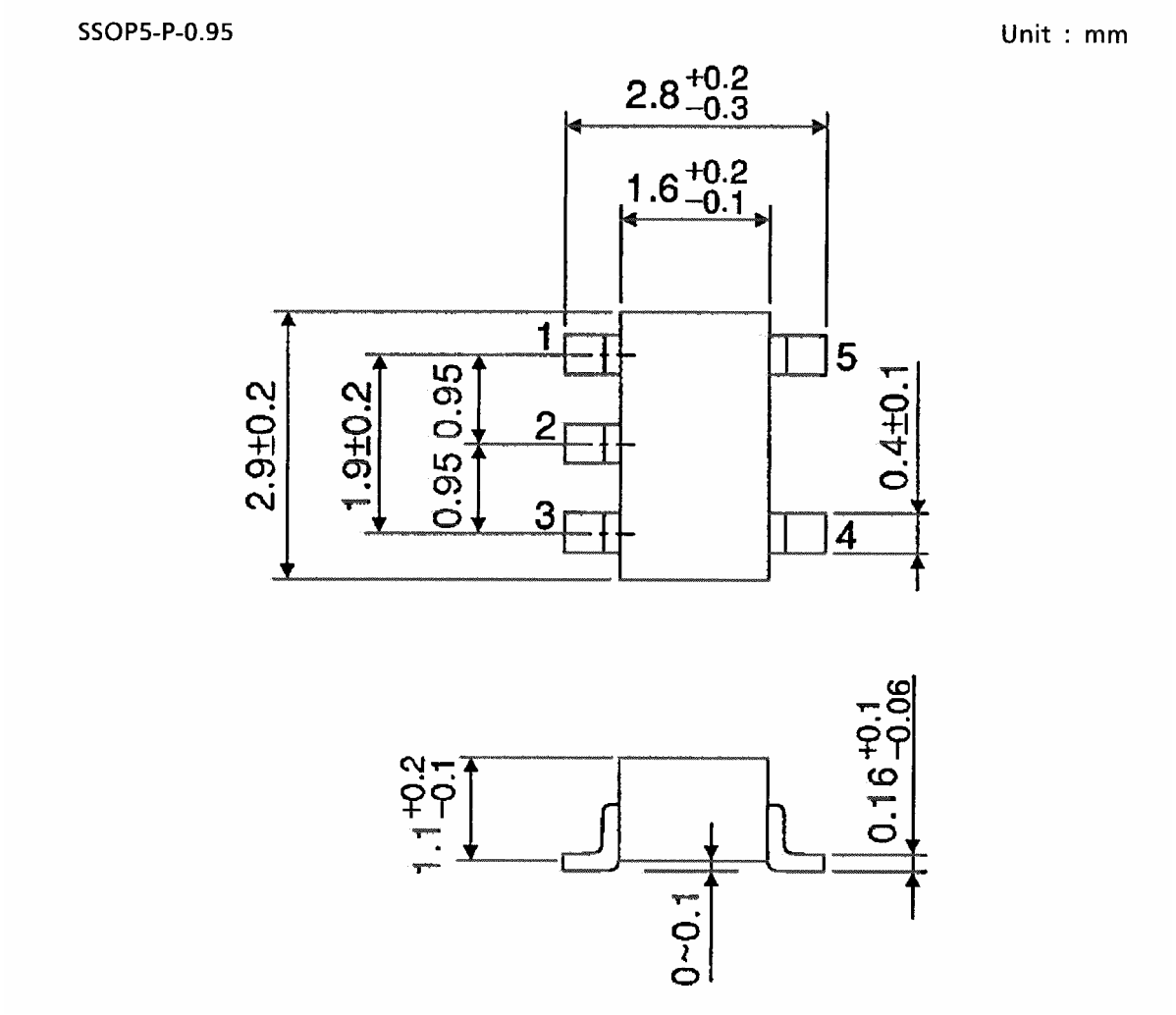
AC Characteristics Measurement Circuit



Characteristics	Switch
t_{pLH}, t_{pHL}	Open
t_{pLZ}, t_{pZL}	$V_{CC} \times 2$
t_{pHZ}, t_{pZH}	GND

Package Dimensions

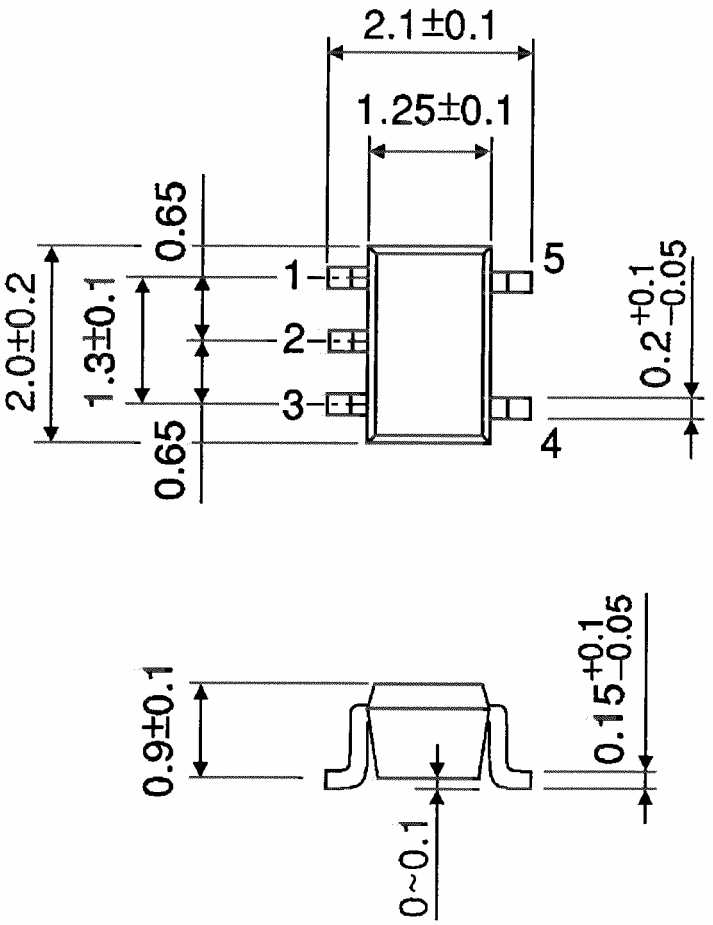
SSOP5-P-0.95 Unit : mm



Weight: 0.016 g (typ.)

Package Dimensions

SSOP5-P-0.65A Unit : mm



Weight: 0.006 g (typ.)

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20070701-EN GENERAL

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